Notice	ωf	References	Cited
NULICE	u	neierences	Citeu

Ī	Application/Control No.	Applicant(s)/Pater	nt Under	
10/644,261		Reexamination ANSARI ET AL.		
	Examiner	Art Unit		
	PRITHAM PRABHAKHER	2622	Page 1 of 1	

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0117501 A1	06-2003	Shirakawa, Hirotsugu	348/218.1
*	В	US-7,425,984 B2	09-2008	Chen et al.	348/159
*	С	US-2004/0196379 A1	10-2004	Chen et al.	348/218.1
*	D	US-6,791,076 B2	09-2004	Webster, Steven	250/239
*	Е	US-6,757,009 B1	06-2004	Simon et al.	348/148
*	F	US-7,002,621 B2	02-2006	Adair et al.	348/158
*	G	US-5,920,337	07-1999	Glassman et al.	348/36
*	Н	US-7,023,913 B1	04-2006	Monroe, David A.	375/240.01
*	_	US-7,015,954 B2	03-2006	Foote et al.	348/218.1
*	J	US-5,898,459	04-1999	Smith et al.	348/219.1
*	к	US-2004/0085445 A1	05-2004	Park, Ho-sang	348/143
*	L	US-2003/0117488 A1	06-2003	Pierce et al.	348/48
	м	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q		l			
	R					
	s					
	Т					

## NON DATENT DOCUMENTS

	NON-PATENT DOCUMENTS			
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U			
	v			
	w			
	x			

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.